



Part Number	Package	Marking
HGP130N12SL	TO-220	

Parameter	Symbol	Value	Unit
Continuous Drain Current (Silicon Limited)	$I_D$	$T_C=25^\circ\text{C}$ 71	
		120	V
		260	A

Symbol

Thermal Resistance Junction-Case

**Electrical Characteristics at  $T_J=25^{\circ}\text{C}$  (unless otherwise specified)**
**Static Characteristics**

Parameter	Symbol	Conditions	Value			Unit
			min	typ	max	
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=250\text{ A}$	120	-	-	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=250\text{ A}$	1.4	2.0	2.4	
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{GS}=0V, V_{DS}=120V, T_J=25^{\circ}\text{C}$	-	-	1	A
		$V_{GS}=0V, V_{DS}=120V, T_J=100^{\circ}\text{C}$	-	-	100	
Gate to Source Leakage Current	$I_{GSS}$	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	$\pm 100$	nA
Drain to Source on Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=20A$	-	9.8	12.5	m
Drain to Source on Resistance	$R_{DS(on)}$	$V_{GS}=4.5V, I_D=20A$	-	12	17	m
Transconductance	$g_{fs}$	$V_{DS}=5V, I_D=20A$	-	65	-	S
Gate Resistance	$R_G$	$V_{GS}=0V, V_{DS}\text{ Open}, f=1\text{MHz}$	-	2.2	-	

**Dynamic Characteristics**

Input Capacitance	$C_{iss}$	$V_{GS}=0V, V_{DS}=60V, f=1\text{MHz}$	-	2056	-	pF
Output Capacitance	$C_{oss}$		-	222	-	
Reverse Transfer Capacitance	$C_{rss}$		-	7.9	-	
Total Gate Charge	$Q_g(10V)$	$V_{DD}=60V, I_D=20A, V_{GS}=10V$	-	31	-	nC
Total Gate Charge	$Q_g(4.5V)$		-	15	-	
Gate to Source Charge	$Q_{gs}$		-	8	-	
Gate to Drain (Miller) Charge	$Q_{gd}$		-	4	-	
Turn on Delay Time	$t_{d(on)}$	$V_{DD}=60V, I_D=20A, V_{GS}=10V, R_G=10\text{ }\Omega$	-	11	-	ns
Rise time	$t_r$		-	9	-	
Turn off Delay Time	$t_{d(off)}$		-	18	-	
Fall Time	$t_f$		-	10	-	

**Reverse Diode Characteristics**

Diode Forward Voltage	$V_{SD}$	$V_{GS}=0V, I_F=20A$	-	0.9	1.2	V
Reverse Recovery Time	$t_{rr}$	$V_R=60V, I_F=20A, dI_F/dt=100A/\text{s}$	-	50	-	ns
Reverse Recovery Charge	$Q_{rr}$		-	75	-	nC

Fig 1. Typical Output Characteristics

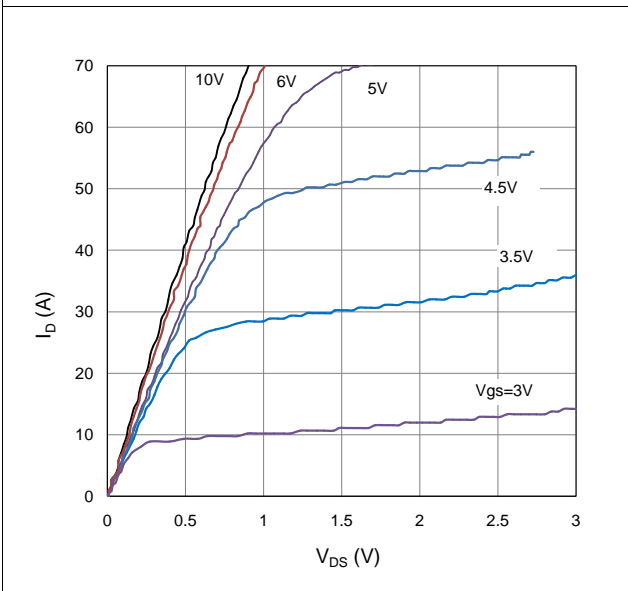


Figure 2. On-Resistance vs. Gate-Source Voltage

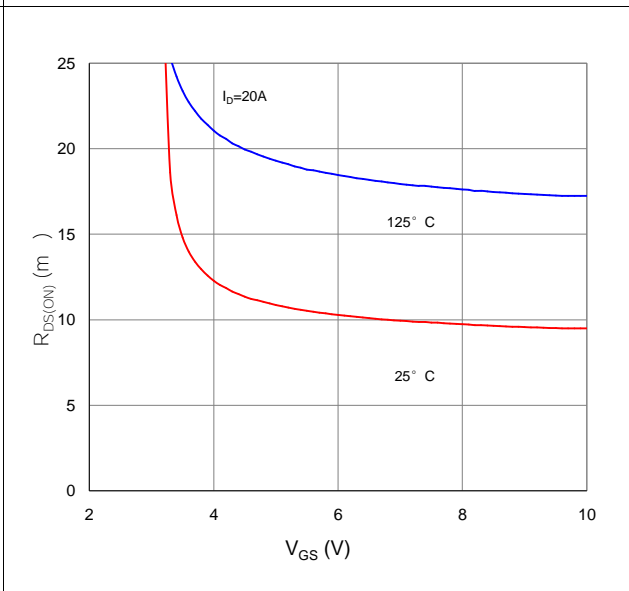


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

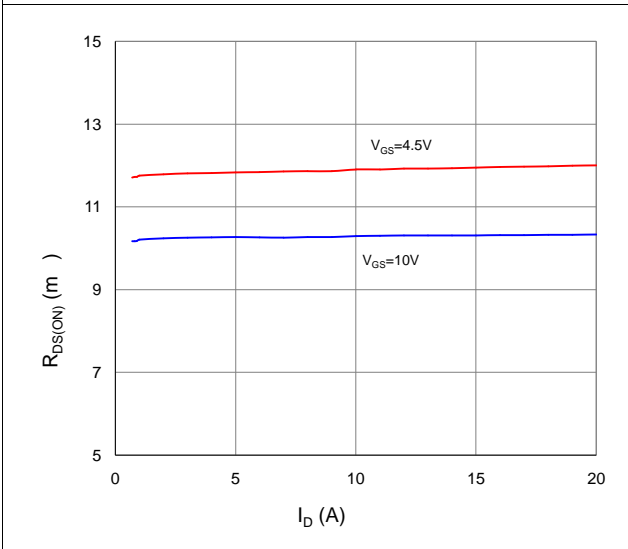


Figure 4. Normalized On-Resistance vs. Junction Temperature

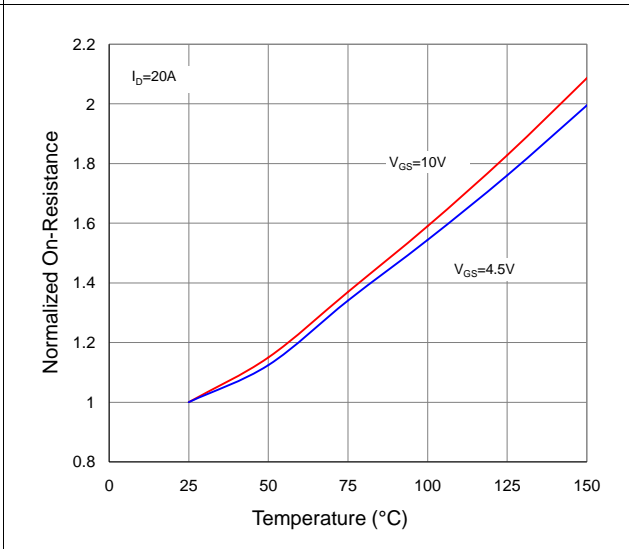


Figure 5. Typical Transfer Characteristics

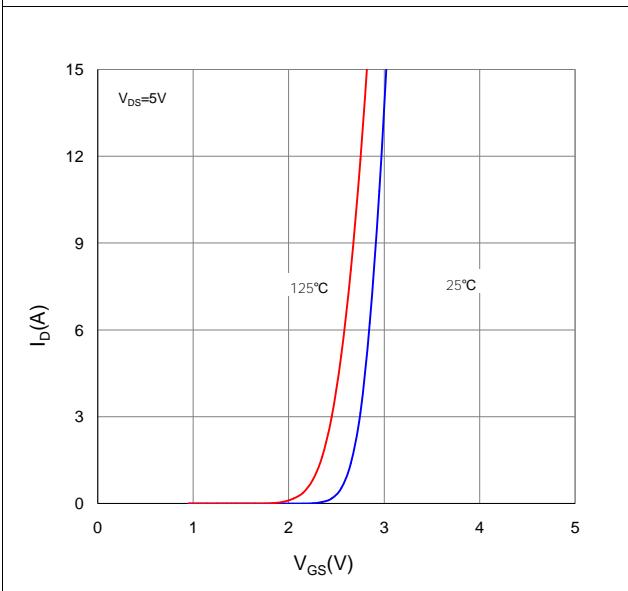


Figure 6. Typical Source-Drain Diode Forward Voltage

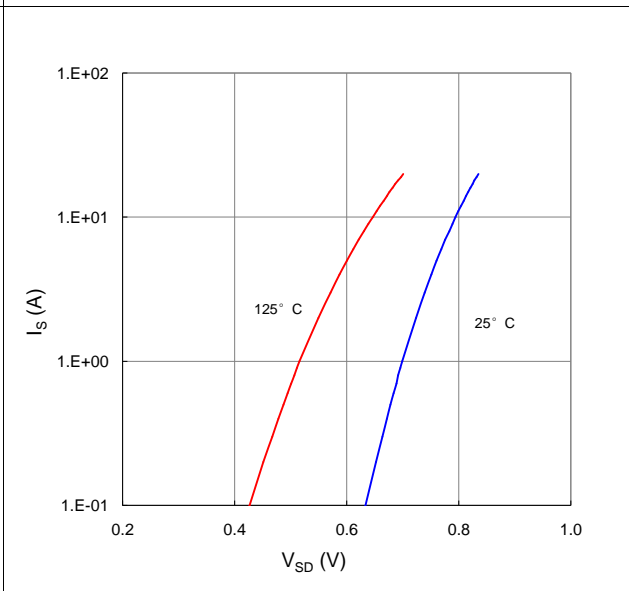


Figure 7. Typical Gate-Charge vs. Gate-to-Source Voltage

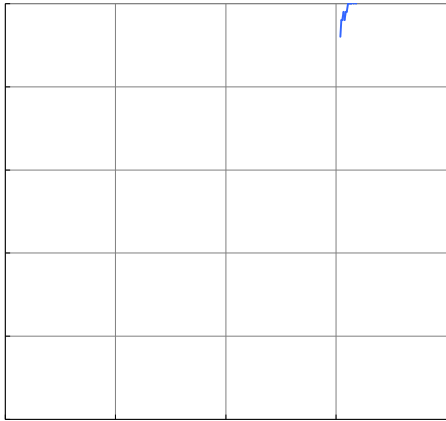


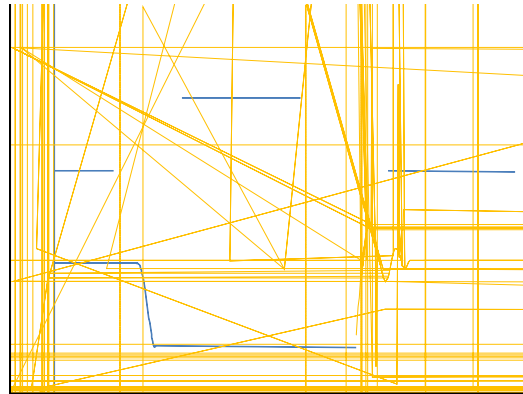
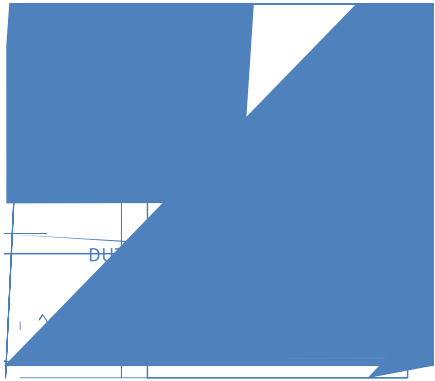
Figure 8. Typical Capacitance vs. Drain-to-Source Voltage

Figure 9. Maximum Safe Operating Area

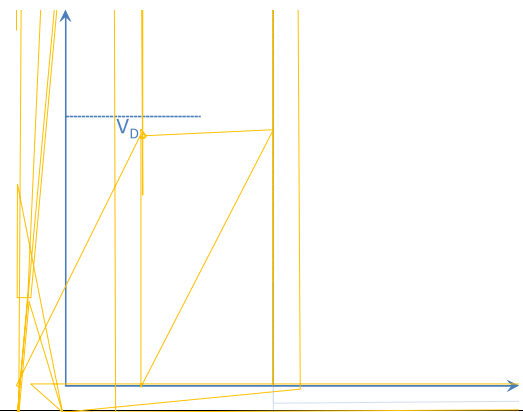
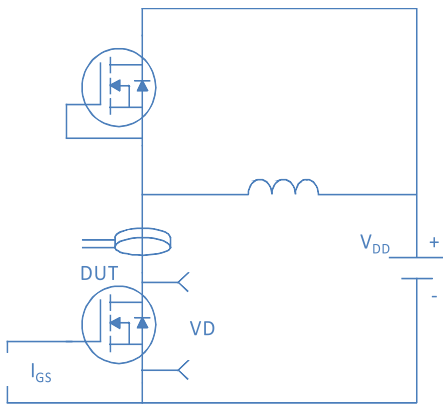
Figure 10. Maximun Drain Current vs. Case Temperature

Figure 11. Normalized Maximum Transient Thermal Impedance, Junction-to-Ambient

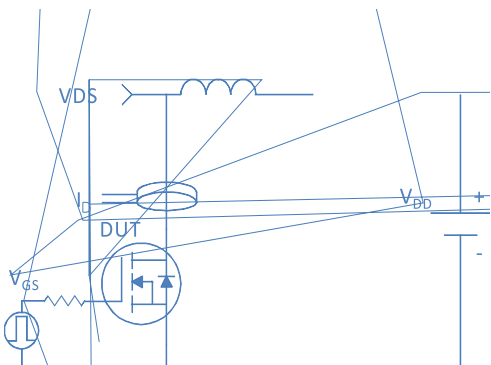
Inductive switching Test



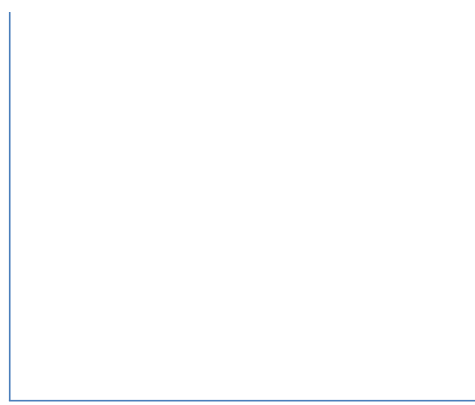
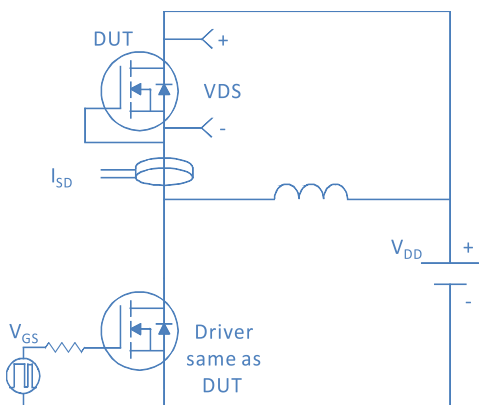
Gate Charge Test



Uclamped Inductive Switching (UIS) Test

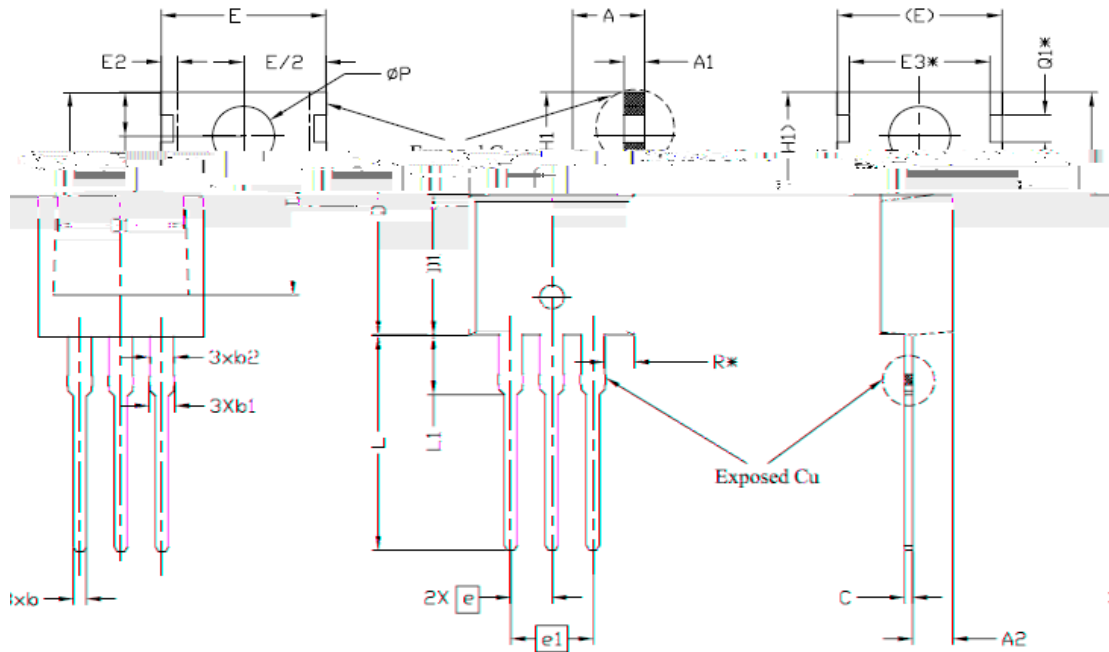


Diode Recovery Test



Package Outline

TO-220, 3 Leads



SYMBOL	DIMENSIONS			NOTES
	MIN.	NOM.	MAX.	
A	4.25	4.54	4.68	
A1	1.08	1.27	1.30	
A2	2.25	2.50	2.75	
b	0.75	1.00	0.60	
b1	1.25	1.50	1.60	
b2	1.25	1.50	1.60	
e	0.50	0.65	0.70	
E	10.20	10.50	10.60	4
E1	5.80	6.00	6.10	
E2	10.50	10.70	10.80	5
E3	6.00	7.10	10.00	4, 5
E4	6.00	7.70	10.00	5
E5			5.20	5
E6		0.70		
e		0.50		
e1		0.30		
H1	4.75	5.00	5.20	5, 6
H2	10.20	10.50	10.60	
H3	5.00	5.50	6.00	
$\phi P$	0.70	0.84	0.90	
$\phi 10$	2.50	2.50	2.50	
R*		0.25		
ixb		1.00		
ixb1		1.00		